Quad buffers; 3-State Rev. 3 — 18 January 2013

**Product data sheet** 

#### 1. **General description**

The 74F125 provides four non-inverting buffer/line drivers with 3-state outputs. The 3-state outputs (nY) are controlled by the output enable input (nOE). A HIGH at nOE causes the outputs to assume a high-impedance OFF-state.

#### 2. **Features and benefits**

■ High impedance NPN base inputs for reduced loading (20 mA in HIGH and LOW states)

### **Ordering information** 3.

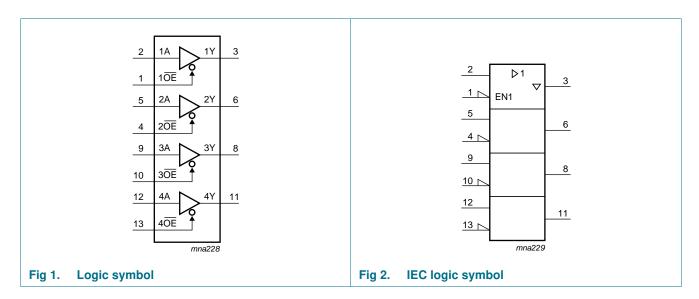
#### Table 1. **Ordering information**

Type number	Package			
	Temperature range	Name	Description	Version
N74F125N	0 °C to +70 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1
N74F125D	0 °C to +70 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1



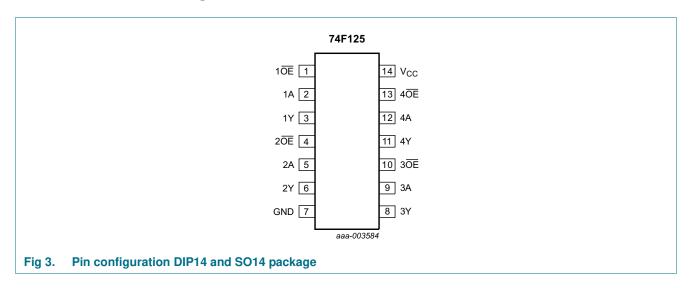
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# 4. Functional diagram



# 5. Pinning information

# 5.1 Pinning



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# 5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description	Unit load HIGH/LOW	Load value[1] HIGH/LOW
1OE to 4OE	1, 4, 10, 13	output enable input (active LOW)	1.0/0.033	20 μΑ/20 μΑ
1A to 4A	2, 5, 9, 12	data input	1.0/0.033	20 μΑ/20 μΑ
1Y to 4Y	3, 6, 8, 11	data output	750/106.7	15 mA/64 mA
GND	7	ground (0 V)	-	-
V <sub>CC</sub>	14	supply voltage	-	-

<sup>[1]</sup> One FAST Unit Load (UL) is defined as 20  $\mu A$  in HIGH state, 0.6  $\mu A$  in LOW state.

# 6. Functional description

Table 3. Function table[1]

Control	Input	Output
nOE	nA	nY
L	L	L
	Н	Н
Н	X	Z

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC}$	supply voltage		-0.5	+7.0	V
VI	input voltage		<u>[1]</u> –0.5	+7.0	V
Vo	output voltage	output in HIGH-state	<u>[1]</u> –0.5	$V_{CC}$	V
I <sub>IK</sub>	input clamping current	$V_I < 0 V$	-30	+5	mA
Io	output current	output in LOW-state	-	128	mA
T <sub>amb</sub>	ambient temperature	in free air	<u>[2]</u> 0	70	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

<sup>[1]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>[2]</sup> The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

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# 8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{CC}$	supply voltage		4.5	5.0	5.5	V
$V_{IH}$	HIGH-level input voltage		2.0	-	-	V
$V_{IL}$	LOW-level input voltage		-	-	0.8	V
I <sub>IK</sub>	input clamping current		-18	-	-	mA
I <sub>OH</sub>	HIGH-level output current		-15	-	-	mA
I <sub>OL</sub>	LOW-level output current		-	-	64	mA
T <sub>amb</sub>	ambient temperature		0		70	°C

# 9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions			25 °C		0 °C to	+70 °C	Unit
			N	/lin	Typ[1]	Max	Min	Max	
$V_{IK}$	input clamping voltage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$	-	1.2	-0.73	-	-1.2	-	V
V <sub>OH</sub>	HIGH-level output	$V_{CC} = 4.5 \text{ V}; V_{IL} = 0.8 \text{ V}; V_{IH} = 2.0 \text{ V}$							
	voltage	$I_{OH} = -3 \text{ mA}$							
		$V_{CC} = \pm 10$ %		-	-	-	2.4	-	V
		V <sub>CC</sub> = ±5 %		-	3.3	-	2.7	-	V
		$I_{OH} = -15 \text{ mA}$							
		V <sub>CC</sub> = ±10 %		-	-	-	2.0	-	V
$V_{OL}$	LOW-level output	$V_{CC} = 4.5 \text{ V}; V_{IL} = 0.8 \text{ V}; V_{IH} = 2.0 \text{ V}$							
	voltage	I <sub>OL</sub> = 64 mA							
		V <sub>CC</sub> = ±10 %		-	-	-	-	0.55	V
		V <sub>CC</sub> = ±5 %		-	0.42	-	-	0.55	V
I <sub>I</sub>	input leakage current	$V_{CC} = 0 \text{ V}; V_I = 7.0 \text{ V}$		-	-	-	-	100	μΑ
I <sub>IH</sub>	HIGH-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 2.7 \text{ V}$		-	-	-	-	20	μΑ
I <sub>IL</sub>	LOW-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 0.5 \text{ V}$		-	-	-	-20	-	μΑ
l <sub>OZ</sub>	OFF-state output current	$V_{CC} = 5.5 \text{ V}$							
		$V_0 = 2.7 \text{ V}$		-	-	-	-	50	μΑ
		$V_0 = 0.5 \text{ V}$		-	-	-	-50	-	μΑ
l <sub>O</sub>	output current	$V_{CC} = 5.5 \text{ V}$	[2]	-	-	-	-225	-100	mA
I <sub>CC</sub>	supply current	$V_{CC} = 5.5 \text{ V}; V_I = \text{GND or } V_{CC}$							
		outputs HIGH-state		-	17	-	-	24	mA
		outputs LOW-state		-	28	-	-	40	mA
		outputs OFF-state		-	25	-	-	35	mA

<sup>[1]</sup> All typical values are measured at  $V_{CC}$  = 5 V.

<sup>[2]</sup> No more than one output should be tested at a time, and the duration of the test should not exceed one second.

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# 10. Dynamic characteristics

Table 7. Dynamic characteristics

GND = 0 V. Test circuit is shown in Figure 6.

Symbol	Parameter	Conditions	25 °C;	V <sub>CC</sub> =	5.0 V	0 °C to +7 V <sub>CC</sub> = 5.0	70 °C; V ± 0.5 V	Unit
			Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	LOW to HIGH propagation delay	nA to nY, see Figure 4	2.0	4.0	6.0	2.0	6.5	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	nA to nY; see Figure 4	3.0	5.5	7.5	3.0	8.0	ns
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	nOE to nY; see Figure 5	3.5	5.5	7.5	3.5	8.5	ns
t <sub>PZL</sub>	OFF-state to LOW propagation delay	nOE to nY; see Figure 5	4.0	6.0	8.0	4.0	9.0	ns
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	nOE to nY; see Figure 5	1.5	3.5	5.0	1.5	6.0	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	nOE to nY; see Figure 5	1.5	3.5	5.5	1.5	6.0	ns

# 11. Waveforms

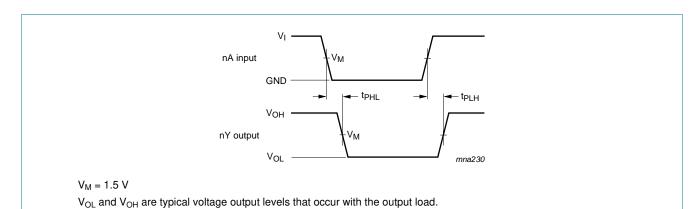
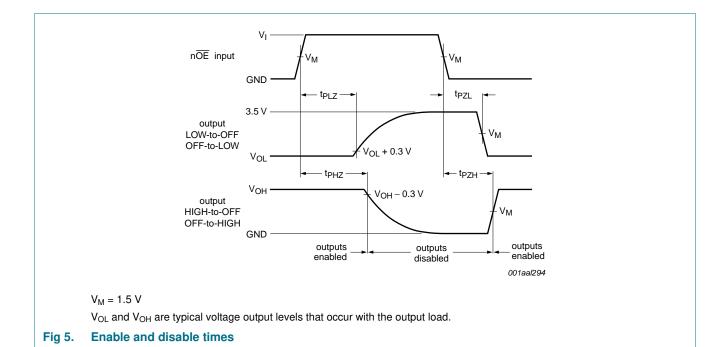
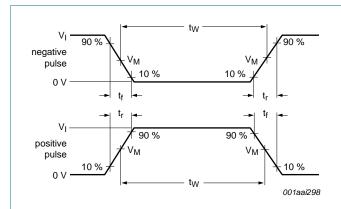
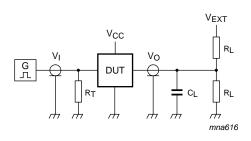


Fig 4. Propagation delay input (nA) to output (nY)

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b. Test circuit

a. Input pulse definition

Test data is given in Table 8.

Test circuit definitions:

R<sub>L</sub> = Load resistance.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to output impedance  $Z_0$  of the pulse generator.

V<sub>EXT</sub> = Test voltage for switching times.

Fig 6. Load circuitry for switching times

Table 8. Test data

$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$				Load		V <sub>EXT</sub>		
$V_{I}$	fi	t <sub>W</sub>	t <sub>r</sub> , t <sub>f</sub>	C <sub>L</sub>	R <sub>L</sub>	t <sub>PHL</sub> , t <sub>PLH</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
3.0 V	1 MHz	500 ns	$\leq$ 2.5 ns	50 pF	$500 \Omega$	open	open	7.0 V

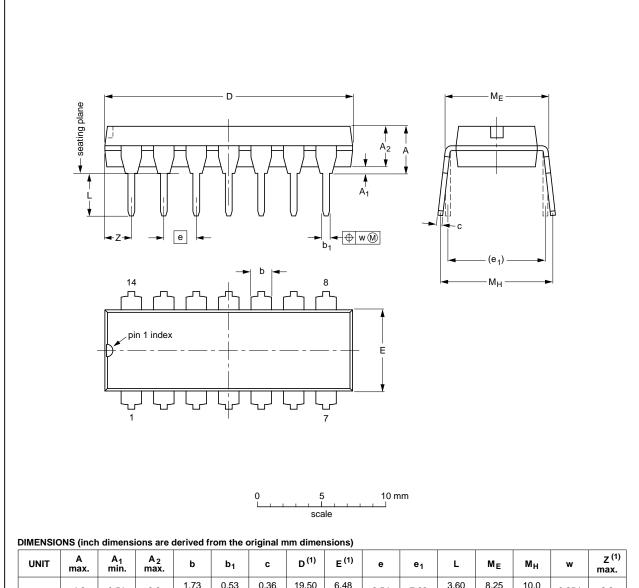
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# 12. Package outline

## DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



	•					•									
UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	С	D <sup>(1)</sup>	E (1)	е	e <sub>1</sub>	L	ME	Мн	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.02	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

### Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE		EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001	SC-501-14			<del>99-12-27</del> 03-02-13

Fig 7. Package outline SOT27-1 (DIP14)

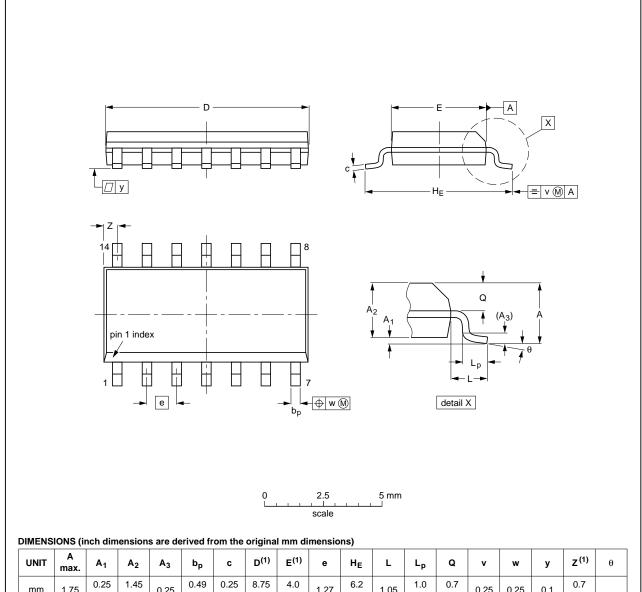
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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	Q	v	w	у	z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01	1	0.0100 0.0075	0.35 0.34	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER						
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE		
SOT108-1	076E06	MS-012				<del>99-12-27</del> 03-02-19		

Fig 8. Package outline SOT108-1 (SO14)

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# 13. Abbreviations

### Table 9. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
LSTTL	Low-power Schottky Transistor-Transistor Logic
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MM	Machine Model
CDM	Charge-Device Model
TTL	Transistor-Transistor Logic

# 14. Revision history

## Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74F125 v.3	20130118	Product data sheet	-	74F125 v.2
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>			
	<ul> <li>Legal texts</li> </ul>	have been adapted to the	new company name whe	ere appropriate.
74F125 v.2	19890328	Product data sheet	-	74F125 v.1

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Product [short] data sheet	Production	This document contains the product specification.

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Product data sheet

Quad buffers: 3-state

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## Quad buffers; 3-state

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